SR#N1, HR#N2, HR#N3 SERIES FOLLOWING EEE-INST-002 LEVEL 1, 2, and 3

QUALITY ASSURANCE PROVISIONS

Every lot undergoes the following inspection and tests.

GROUP 1

- 1. Thermal shock before Voltage conditioning, (SR#N1, HR#N2,): MIL-STD-202 Method 107 Condition B (-55/+125°C).
- 2. Voltage Conditioning at 125°C, SR#N1: 160Hrs, HR#N2: 96Hrs, HR#N3: 48Hrs. Vtest = 2X rated for ≤ 500V, 1.2X rated for 501 to 999V. 1X rated ≥ 1000V.
- 3. Capacitance (SR#N1, HR#N2, HR#N3): all parts are tested at 25°C and 1 VACRMS in accordance with Method 305 of MIL-STD-202.
- 4. Dissipation Factor, DF, (SR#N1, HR#N2, HR#N3): Capacitance: all parts are tested at 25°C and 1 VACRMS in accordance with Method 305 of MIL-STD-202
- 5. Dielectric Withstanding Voltage, DWM, (SR#N1, HR#N2, HR#N3): MIL-STD-202 Method 301. Test is performed at 2.5X rated voltage for rating below 500V.
- 6. Insulation Resistance 1, (SR#N1, HR#N2, HR#N3): MIL-STD-202 Method 301, room temperature.
- 7. Insulation Resistance 2, (SR#N1): MIL-STD-202 Method 301, repeat at max. rated temp. (125°C).
- 8. Percentage Defective Allowed (PDA): SR#N1: 5%, HR#N2: 10%, HR#N3: 20%.
- 9. Radiographic inspection: For SR#N1 leaded parts only, not applicable for SMD Chips.
- 10. Visual and Mechanical Examination (SR#N1, HR#N2).

GROUP 2

- Voltage/Temperature Limit (SR#N1-12(1) pcs, HR#N2 6(1) pcs), Not applicable to X7R.
- Temperature Coefficient and Drift (SR#N1- HR#N2), N/A for BX/BR/BQ/BZ/X7R parts.

GROUP 3

- Terminal Strength: N/A for surface mount chips.
- Resistance to Solder Heat (SR#N1, HR#N2): MIL-STD-202, Method 210 Condition C (chips). Condition G (Leaded).
- Moisture Resistance (SR#N1-12(0), HR#N2 6(0)): MIL-STD-202, Method 106. Exception: For size ≤ 0603 test is performed on larger size parts cut from the same wafer. Test voltage is rated voltage or 50V whichever is less.

GROUP 4

Humidity Steady State Low Voltage (SR#N1-12(0) pcs, HR#N2-5(0) pcs), MIL-STD-202 Method 103 Condition A and MIL-PRF-123 Group B

GROUP 5

- Solderability (SR#N1-5(0) pcs, HR#N2-3(0) pcs): MIL-STD-202, Method 208
- Destructive Physical Analysis: (SR#N1): EIA-469 Exception: Use separate pieces for Solderability Test 5(0) and DPA.

GROUP 6

- Life (at elevated temperature: 125°C), (SR#N1–2000H, 22(0) pcs, HR#N2-1000H, 22(1)) pcs): Vtest = 2X rated for $\leq 500V$, 1.2X rated for 501 to 999V, 1X rated ≥ 1000V
- Partial Discharge aka Corona Test for SR#N1 and HR#N2 for voltage rating ≥ 1000V

MARKING (Optional for sizes 0805 and larger only) - Parts will not be marked unless marking is specified on the PO. If marking is specified, a color letter will be used per Presidio's chip marking system.

STANDARD PACKAGING

Product will be packaged in individual waffle trays. Tape and reel option is available.

DATA PACKAGE

Level/Series	Level 1 Series SR#N1	Level 2 Series HR#N2	Level 3 Series HR#N3
Certificate of Conformity	YES	YES	YES
DPA Report	YES	NO	NO
Group 1 to 6 Data when Applicable	YES	YES	NO

PART NUMBER EXAMPLE HR0402X7R104KENT91(D)#N2

PART DESCRIPTION: HR, 0402, X7R, 0.12μF, ±10%, 10V, Plated SnPb Over Ni Termination, Tape & Reel, Design-In Code (D) for Arizona, Screened following EEE-INST-002 Level 2.

C OF C AND DATA PACK INCLUDED WITH THE PARTS.

HOW TO ORDER

See Website for Design-In Codes

